

Dual J-K negative edge-triggered flip-flops without reset

74F113

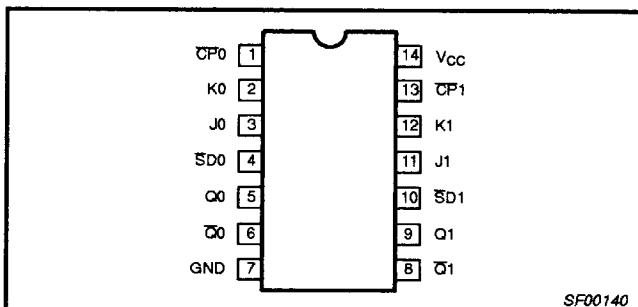
FEATURE

- Industrial temperature range available (-40°C to +85°C)

DESCRIPTION

The 74F113, dual negative edge-triggered JK-type flip-flop, features individual J, K, clock (CP), set (SD) inputs, true and complementary outputs. The asynchronous SD input, when low, forces the outputs to the steady state levels as shown in the function table regardless of the level at the other inputs.

A high level on the clock (CP) input enables the J and K inputs and data will be accepted. The logic levels at the J and K inputs may be allowed to change while the CP is high and flip-flop will perform according to the function table as long as minimum setup and hold times are observed. Output changes are initiated by the high-to-low transition of the CP.

PIN CONFIGURATION

SF00140

TYPE	TYPICAL f_{max}	TYPICAL SUPPLY CURRENT (TOTAL)
74F113	100MHz	15mA

ORDERING INFORMATION

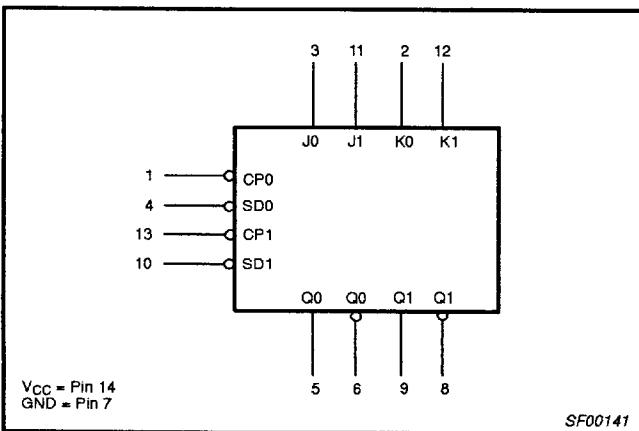
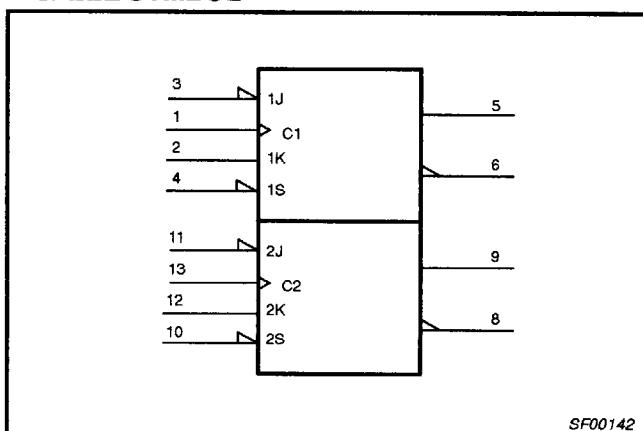
DESCRIPTION	ORDER CODE		PKG. DWG. #
	COMMERCIAL RANGE $V_{CC} = 5V \pm 10\%$, $T_{amb} = 0^\circ C$ to $+70^\circ C$	INDUSTRIAL RANGE $V_{CC} = 5V \pm 10\%$, $T_{amb} = -40^\circ C$ to $+85^\circ C$	
14-pin plastic DIP	N74F113N	I74F113N	SOT27-1
14-pin plastic SO	N74F113D	I74F113D	SOT108-1

INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

PINS	DESCRIPTION	74F (U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
J0, J1	J inputs	1.0/1.0	20µA/0.6mA
K0, K1	K inputs	1.0/1.0	20µA/0.6mA
CP0, CP1	Clock inputs (active falling edge)	1.0/4.0	20µA/2.4mA
SD0, SD1	Set inputs (active low)	1.0/5.0	20µA/3.0mA
Q0, Q1, Q0-bar, Q1-bar	Data outputs	50/33	1.0mA/20mA

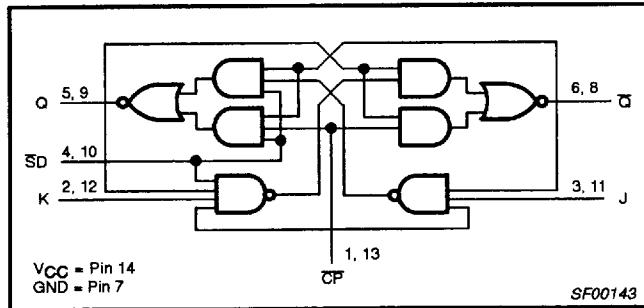
NOTE:

One (1.0) FAST unit load is defined as: 20µA in the High state and 0.6mA in the Low state.

LOGIC SYMBOL**IEC/IEEE SYMBOL**

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LOGIC DIAGRAM**FUNCTION TABLE**

SD	CP	INPUTS		OUTPUTS		OPERATING MODE
		J	K	Q	Q̄	
L	X	X	X	H	L	Asynchronous set
H	↓	h	h	Q̄	q	Toggle
H	↓	h	I	H	L	Load "1" (set)
H	↓	I	h	L	H	Load "0" (reset)
H	↓	I	I	q	Q̄	Hold 'no change'

NOTES:

1. H = High-voltage level
2. h = High-voltage level one setup time prior to high-to-low clock transition
3. L = Low-voltage level
4. I = Low-voltage level one setup time prior to high-to-low clock transition
5. q = Lower case indicate the state of the referenced output prior to the high-to-low clock transition
6. X = Don't care
7. ↓ = high-to-low clock transition

ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limits set forth in this table may impair the useful life of the device.

Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V _{CC}	Supply voltage	-0.5 to +7.0	V
V _{IN}	Input voltage	-0.5 to +7.0	V
I _{IN}	Input current	-30 to +5	mA
V _{OUT}	Voltage applied to output in High output state	-0.5 to V _{CC}	V
I _{OUT}	Current applied to output in Low output state	40	mA
T _{amb}	Operating free-air temperature range	Commercial range	°C
		Industrial range	°C
T _{stg}	Storage temperature range	-65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS			UNIT
		MIN	NOM	MAX	
V _{CC}	Supply voltage	4.5	5.0	5.5	V
V _{IH}	High-level input voltage	2.0			V
V _{IL}	Low-level input voltage			0.8	V
I _{IK}	Input clamp current			-18	mA
I _{OH}	High-level output current			-1	mA
I _{OL}	Low-level output current			20	mA
T _{amb}	Operating free-air temperature range	Commercial range	0	+70	°C
		Industrial range	-40	+85	°C

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DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER	TEST CONDITIONS ¹			LIMITS			UNIT
					MIN	TYP ²	MAX	
V _{OH}	High-level output voltage	V _{CC} = MIN, V _{IL} = MAX, V _{IH} = MIN	I _{OH} = MAX	±10%V _{CC}	2.5			V
				±5%V _{CC}	2.7	3.4		V
V _{OL}	Low-level output voltage	V _{CC} = MIN, V _{IL} = MAX, V _{IH} = MIN	I _{OL} = MAX	±10%V _{CC}		0.30	0.50	V
				±5%V _{CC}		0.30	0.50	V
V _{IK}	Input clamp voltage	V _{CC} = MIN, I _I = I _{JK}				-0.73	-1.2	V
I _I	Input current at maximum input voltage	V _{CC} = MAX, V _I = 7.0V					100	μA
I _{IH}	High-level input current	V _{CC} = MAX, V _I = 2.7V					20	μA
I _{IL}	Low-level input current	Jn, Kn	V _{CC} = MAX, V _I = 0.5V				-0.6	mA
		CPn					-2.4	mA
		SDn					-3.0	mA
I _{OS}	Short-circuit output current ³	V _{CC} = MAX			-60		-150	mA
I _{CC}	Supply current ⁴ (total)	V _{CC} = MAX				15	21	mA

NOTES:

1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
2. All typical values are at V_{CC} = 5V, T_{amb} = 25°C.
3. Not more than one output should be shorted at a time. For testing I_{OS}, the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a high output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.
4. Measure I_{CC} with the clock input grounded and all outputs open, then with Q and \bar{Q} outputs high in turn.

AC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITION	LIMITS						UNIT	
			V _{CC} = +5.0V T _{amb} = +25°C C _L = 50pF R _L = 500Ω			V _{CC} = +5.0V ± 10% T _{amb} = 0°C to +70°C C _L = 50pF R _L = 500Ω		V _{CC} = +5.0V ± 10% T _{amb} = -40°C to +85°C C _L = 50pF R _L = 500Ω		
			MIN	TYP	MAX	MIN	MAX	MIN		
f _{max}	Maximum clock frequency	Waveform 1	85	100		80		80	ns	
t _{PLH} t _{PHL}	Propagation delay CPn to Qn or \bar{Q} n	Waveform 1	2.0 2.0	4.0 4.0	6.0 6.0	2.0 2.0	7.0 7.0	2.0 2.0	7.5 7.0	
t _{PLH} t _{PHL}	Propagation delay SDn, to Qn or \bar{Q} n	Waveform 2	2.0 2.0	4.5 4.5	6.5 6.5	2.0 2.0	7.5 7.5	2.0 2.0	8.0 7.5	

AC SETUP REQUIREMENTS

SYMBOL	PARAMETER	TEST CONDITION	LIMITS						UNIT	
			V _{CC} = +5.0V T _{amb} = +25°C C _L = 50pF R _L = 500Ω			V _{CC} = +5.0V ± 10% T _{amb} = 0°C to +70°C C _L = 50pF R _L = 500Ω		V _{CC} = +5.0V ± 10% T _{amb} = -40°C to +85°C C _L = 50pF R _L = 500Ω		
			MIN	TYP	MAX	MIN	MAX	MIN		
t _{su} (H) t _{su} (L)	Setup time, high or low Jn, Kn to CPn	Waveform 1	4.0 3.5			5.0 4.0		5.0 4.5	ns	
t _h (H) t _h (L)	Hold time, high or low Jn, Kn to CPn	Waveform 1	0.0 0.0			0.0 0.0		0.0 0.0	ns	
t _w (H) t _w (L)	CP pulse width, high or low	Waveform 1	4.5 4.5			5.0 5.0		5.0 5.0	ns	
t _w (L)	SDn pulse width, low	Waveform 2	4.5			5.0		5.0	ns	
t _{rec}	Recovery time SDn to CPn	Waveform 2	4.5			5.0		5.0	ns	

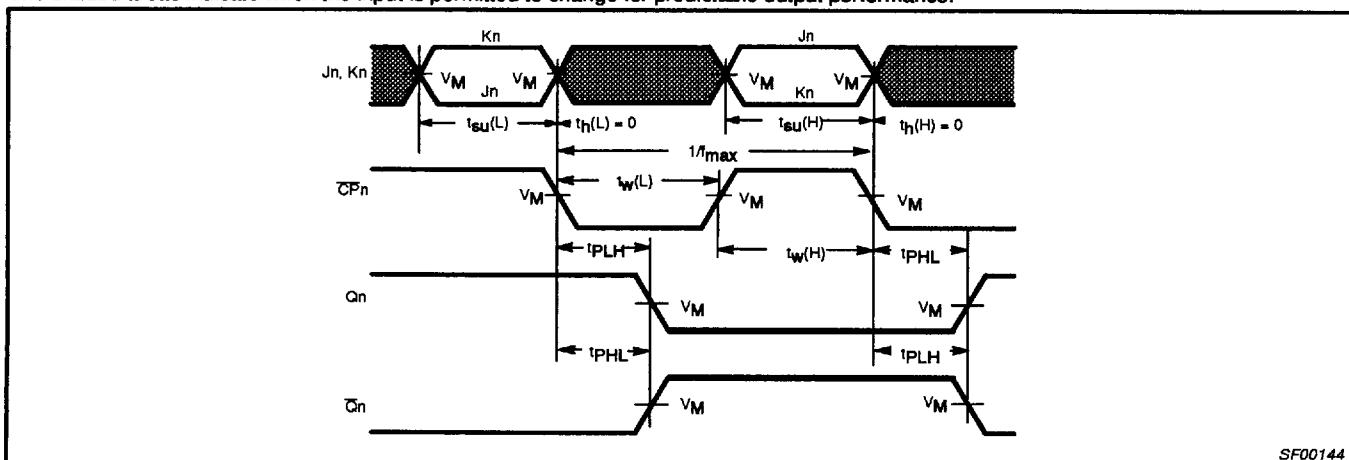
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AC WAVEFORMS

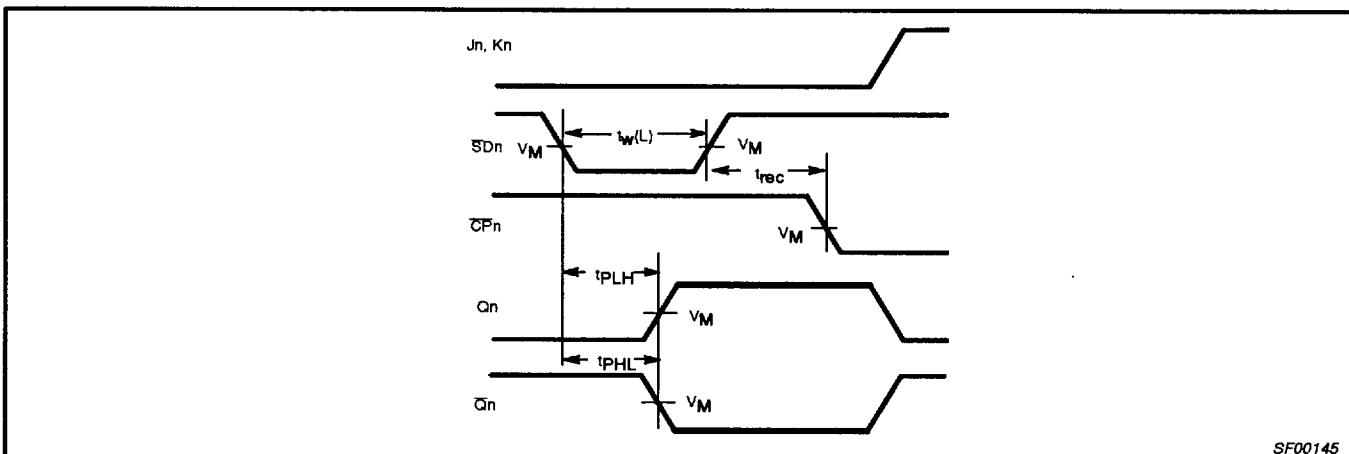
For all waveforms, $V_M = 1.5V$.

The shaded areas indicate when the input is permitted to change for predictable output performance.



SF00144

Waveform 1. Propagation Delay for Data to Output, Data Setup Time and Hold Times, and Clock Width, and Maximum Clock Frequency



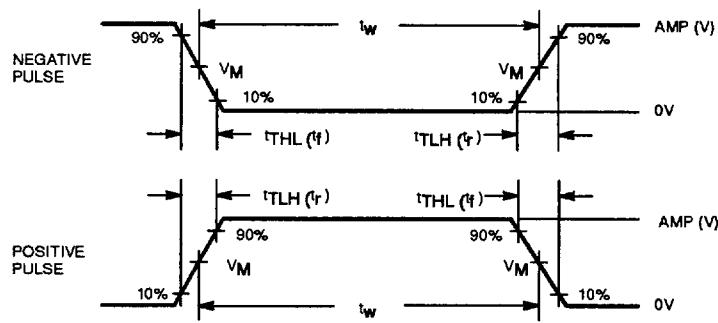
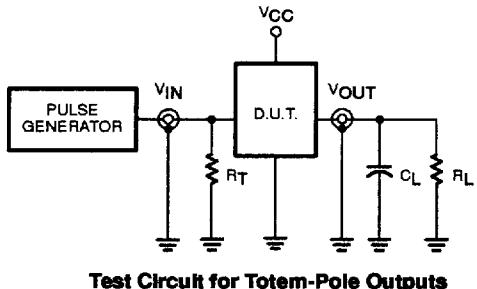
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Waveform 2. Propagation Delay for Set to Output, Set Pulse Width, and Recovery Time for Set to Clock

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TEST CIRCUIT AND WAVEFORMS


DEFINITIONS:

R_L = Load resistor;

see AC ELECTRICAL CHARACTERISTICS for value.

C_L = Load capacitance includes jig and probe capacitance;
see AC ELECTRICAL CHARACTERISTICS for value.

R_T = Termination resistance should be equal to Z_{OUT} of
pulse generators.

family	INPUT PULSE REQUIREMENTS					
	amplitude	V_M	rep. rate	t_w	t_{TLH}	t_{THL}
74F	3.0V	1.5V	1MHz	500ns	2.5ns	2.5ns

SF00006